12-Channel, 1:2 MUX/DEMUX Switch for DDR3 Applications

Check for Samples: TS3DDR3812

**FEATURES**

- Compatible with DDR3 SDRAM Standard (JESD79-3D)
- Wide Bandwidth of 1.675 GHz
- Low Propagation Delay ($t_{pd} = 40$ ps Typ)
- Low Bit-to-Bit Skew ($t_{sk(o)} = 6$ ps Typ)
- Low and Flat ON-State Resistance ($r_{ON} = 8$ Ω Typ)
- Low Input/Output Capacitance ($C_{ON} = 5.6$ pF Typ)
- Low Crosstalk ($X_{TALK} = -43$ dB, Typ at 250 MHz)
- $V_{CC}$ Operating Range from 3 V to 3.6 V
- Rail-to-Rail Switching on Data I/O Ports (0 to $V_{CC}$)
- Separate Switch Control Logic for Upper and Lower 6-Channels
- Dedicated Enable Logic Supports Hi-Z Mode
- $I_{OFF}$ Protection Prevents Current Leakage in Powered Down State ($V_{CC} = 0$ V)
- ESD Performance Tested Per JESD22
  - 2000 V Human Body Model (A114B, Class II)
  - 1000 V Charged Device Model (C101)
- 42-pin RUA Package (9 × 3.5 mm, 0.5 mm Pitch)

**APPLICATIONS**

- DDR3 Signal Switching
- DIMM Modules
- Notebook/Desktop PCs
- Servers

**DESCRIPTION**

The TS3DDR3812 is a 12-channel, 1:2 multiplexer/demultiplexer switch designed for DDR3 applications. It operates from a 3 to 3.6 V supply and offers low and flat ON-state resistance as well as low I/O capacitance which allow it to achieve a typical bandwidth of 1.675 GHz.

Channels A0 through A11 are divided into two banks of six bits and are independently controlled via two digital inputs called SEL1 and SEL2. These select inputs control the switch position of each 6-bit DDR3 source and allow them to be routed to one of two end-points. Alternatively, the switch can be used to connect a single endpoint to one of two 6-bit DDR3 sources. For switching 12-bit DDR3 sources, simply connect SEL1 and SEL2 together externally and control all 12 channels with a single GPIO input. An EN input allows the entire chip to be placed into a high-impedance (Hi-Z) state while not in use.

These characteristics make the TS3DDR3812 an excellent choice for use in memory, analog/digital video, LAN, and other high-speed signal switching applications.

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Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.
These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

**ORDERING INFORMATION**

For package and ordering information, see the Package Option Addendum at the end of this document.

**Figure 2. LOGIC DIAGRAM**

**FUNCTION TABLE**

<table>
<thead>
<tr>
<th>EN</th>
<th>SEL1</th>
<th>SEL2</th>
<th>FUNCTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>L</td>
<td>X</td>
<td>X</td>
<td>A₀ to A₁₁, B₀ to B₁₁, and C₀ to C₁₁ are Hi-Z</td>
</tr>
<tr>
<td>H</td>
<td>L</td>
<td>L</td>
<td>A₀ to A₅ = B₀ to B₅ and A₆ to A₁₁ = B₆ to B₁₁</td>
</tr>
<tr>
<td>H</td>
<td>L</td>
<td>H</td>
<td>A₀ to A₅ = B₀ to B₅ and A₆ to A₁₁ = C₆ to C₁₁</td>
</tr>
<tr>
<td>H</td>
<td>H</td>
<td>L</td>
<td>A₀ to A₅ = C₀ to C₅ and A₆ to A₁₁ = B₆ to B₁₁</td>
</tr>
<tr>
<td>H</td>
<td>H</td>
<td>H</td>
<td>A₀ to A₅ = C₀ to C₅ and A₆ to A₁₁ = C₆ to C₁₁</td>
</tr>
</tbody>
</table>

**TERMINAL FUNCTIONS**

<table>
<thead>
<tr>
<th>PIN</th>
<th>NAME</th>
<th>NUMBER</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>Vcc</td>
<td>Vcc</td>
<td>1,17, 30</td>
<td>Supply Voltage</td>
</tr>
<tr>
<td>GND</td>
<td>GND</td>
<td></td>
<td>ThermalPad</td>
</tr>
<tr>
<td></td>
<td></td>
<td></td>
<td>Ground</td>
</tr>
</tbody>
</table>
## TERMINAL FUNCTIONS (continued)

<table>
<thead>
<tr>
<th>PIN</th>
<th>DESCRIPTION</th>
<th>NAME</th>
<th>NUMBER</th>
</tr>
</thead>
<tbody>
<tr>
<td>EN</td>
<td>Enable Input</td>
<td>8</td>
<td></td>
</tr>
<tr>
<td>SEL1</td>
<td>Select Input</td>
<td>9</td>
<td></td>
</tr>
<tr>
<td>SEL2</td>
<td>Select Input</td>
<td>10</td>
<td></td>
</tr>
<tr>
<td>A0, A1, A2, A3, A4, A5, A6, A7, A8, A9, A10, A11</td>
<td>2, 3, 4, 5, 6, 7, 11, 12, 13, 14, 15, 16</td>
<td>Data I/Os</td>
<td></td>
</tr>
<tr>
<td>B0, B1, B2, B3, B4, B5, B6, B7, B8, B9, B10, B11</td>
<td>41, 39, 38, 36, 34, 32, 29, 27, 25, 23, 21, 19</td>
<td>Data I/Os</td>
<td></td>
</tr>
<tr>
<td>C0, C1, C2, C3, C4, C5, C6, C7, C8, C9, C10, C11</td>
<td>42, 40, 37, 35, 33, 31, 28, 26, 24, 22, 20, 18</td>
<td>Data I/Os</td>
<td></td>
</tr>
</tbody>
</table>

### ABSOLUTE MAXIMUM RATINGS(1)

Over operating free-air temperature range (unless otherwise noted)

<table>
<thead>
<tr>
<th>Parameter</th>
<th>MIN</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>V&lt;sub&gt;CC&lt;/sub&gt; Supply voltage range</td>
<td>–0.5</td>
<td>4.6</td>
<td>V</td>
</tr>
<tr>
<td>V&lt;sub&gt;I/O&lt;/sub&gt; Analog voltage range</td>
<td>–0.5</td>
<td>7</td>
<td>V</td>
</tr>
<tr>
<td>V&lt;sub&gt;IN&lt;/sub&gt; Digital input voltage range</td>
<td>–0.5</td>
<td>7</td>
<td>V</td>
</tr>
<tr>
<td>I&lt;sub&gt;LEAK&lt;/sub&gt; Analog port diode current</td>
<td>V&lt;sub&gt;I/O&lt;/sub&gt; &lt; 0</td>
<td>–50</td>
<td>mA</td>
</tr>
<tr>
<td>I&lt;sub&gt;IK&lt;/sub&gt; Digital input clamp current</td>
<td>V&lt;sub&gt;IN&lt;/sub&gt; &lt; 0</td>
<td>–50</td>
<td>mA</td>
</tr>
<tr>
<td>I&lt;sub&gt;IO&lt;/sub&gt; On-state switch current</td>
<td>A, B, C</td>
<td>–128</td>
<td>128</td>
</tr>
<tr>
<td>I&lt;sub&gt;DD&lt;/sub&gt;, I&lt;sub&gt;GND&lt;/sub&gt; Continuous current through V&lt;sub&gt;DD&lt;/sub&gt; or GND</td>
<td>–100</td>
<td>100</td>
<td>mA</td>
</tr>
<tr>
<td>θ&lt;sub&gt;JA&lt;/sub&gt; Package thermal impedance</td>
<td>RUA package</td>
<td>31.8</td>
<td>°C/W</td>
</tr>
<tr>
<td>T&lt;sub&gt;stg&lt;/sub&gt; Storage temperature range</td>
<td>–65</td>
<td>150</td>
<td>°C</td>
</tr>
</tbody>
</table>

(1) Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "Recommended Operating Conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to ground, unless otherwise specified.

(3) The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

(4) V<sub>I</sub> and V<sub>O</sub> are used to denote specific conditions for V<sub>I/O</sub>.

(5) I<sub>I</sub> and I<sub>O</sub> are used to denote specific conditions for I<sub>I/O</sub>.

(6) The package thermal impedance is calculated in accordance with JESD 51-7.
RECOMMENDED OPERATING CONDITIONS\(^{(1)}\)

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>MIN</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>(V_{CC}) Supply voltage</td>
<td>3</td>
<td>3.6</td>
<td>V</td>
</tr>
<tr>
<td>(V_{IH}) High-level control input voltage</td>
<td>SEL1, SEL2</td>
<td>2</td>
<td>5.5</td>
</tr>
<tr>
<td>(V_{IL}) Low-level control input voltage</td>
<td>SEL1, SEL2</td>
<td>0</td>
<td>0.8</td>
</tr>
<tr>
<td>(V_{IN}) Input voltage</td>
<td>SEL1, SEL2</td>
<td>0</td>
<td>5.5</td>
</tr>
<tr>
<td>(V_{IO}) Input/Output voltage</td>
<td>0</td>
<td>(V_{CC})</td>
<td></td>
</tr>
<tr>
<td>(T_A) Operating free-air temperature</td>
<td>–40</td>
<td>85</td>
<td>°C</td>
</tr>
</tbody>
</table>

(1) All unused control inputs of the device must be held at \(V_{DD}\) or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

ELECTRICAL CHARACTERISTICS

over recommended operating free-air temperature range, \(V_{CC} = 3.3 \pm 0.3\) V (unless otherwise noted)

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>TEST CONDITIONS(^{(1)})</th>
<th>MIN</th>
<th>TYP(^{(2)})</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>(V_{IK}) Digital input clamp voltage</td>
<td>(V_{CC} = 3.6) V, (I_{IN} = -18) mA</td>
<td>–1.2</td>
<td>–0.8</td>
<td>V</td>
<td></td>
</tr>
<tr>
<td>(R_{ON}) ON-state resistance</td>
<td>(A, B, C) (V_{CC} = 3) V, (1.5) V (\leq V_{IO} \leq V_{CC}), (I_{IO} = -40) mA</td>
<td>8</td>
<td>12</td>
<td>Ω</td>
<td></td>
</tr>
<tr>
<td>(R_{ON(FLAT)}) ON-state resistance flatness</td>
<td>(A, B, C) (V_{CC} = 3) V, (V_{IO} = 1.5) V and (V_{CC}), (I_{IO} = -40) mA</td>
<td>1.5</td>
<td>Ω</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(\Delta R_{ON}) On-state resistance match between channels</td>
<td>(A, B, C) (V_{CC} = 3) V, (1.5) V (\leq V_{IO} \leq V_{CC}), (I_{IO} = -40) mA</td>
<td>0.4</td>
<td>1</td>
<td>Ω</td>
<td></td>
</tr>
<tr>
<td>(I_{IH}) Digital input high leakage current</td>
<td>SEL1, SEL2 (V_{CC} = 3.6) V, (V_{IN} = V_{DD})</td>
<td>±1</td>
<td>μA</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(I_{IL}) Digital input low leakage current</td>
<td>SEL1, SEL2 (V_{CC} = 3.6) V, (V_{IN} = GND)</td>
<td>±1</td>
<td>μA</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(I_{OFF}) Leakage under power off conditions</td>
<td>All outputs (V_{CC} = 0) V, (V_{IO} = 0) to 3.6 V, (V_{IN} = 0) to 5.5 V</td>
<td>±1</td>
<td>μA</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(C_{IN}) Digital input capacitance</td>
<td>SEL1, SEL2 (f = 1) MHz, (V_{IN} = 0) V</td>
<td>2.6</td>
<td>3.2</td>
<td>pF</td>
<td></td>
</tr>
<tr>
<td>(C_{OFF}) Switch OFF capacitance</td>
<td>(A, B, C) (f = 1) MHz, (V_{IO} = 0) V, Output is open, Switch is OFF</td>
<td>2</td>
<td>pF</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(C_{ON}) Switch ON capacitance</td>
<td>(A, B, C) (f = 1) MHz, (V_{IO} = 0) V, Output is open, Switch is ON</td>
<td>5.6</td>
<td>pF</td>
<td></td>
<td></td>
</tr>
<tr>
<td>(I_{CC}) (V_{CC}) supply current</td>
<td>(V_{CC} = 3.6) V, (I_{IO} = 0), (V_{IN} = V_{DD}) or GND</td>
<td>300</td>
<td>400</td>
<td>μA</td>
<td></td>
</tr>
</tbody>
</table>

(1) \(V_{I}, V_{O}, I_{I}, \) and \(I_{O}\) refer to I/O pins, \(V_{IN}\) refers to the control inputs
(2) All typical values are at \(V_{CC} = 3.3\) V (unless otherwise noted), \(T_A = 25^\circ\)C
(3) \(R_{ON(FLAT)}\) is the difference of \(R_{ON}\) in a given channel at specified voltages.
(4) \(\Delta R_{ON}\) is the difference of \(R_{ON}\) from center port (A5, A6) to any other ports.
SWITCHING CHARACTERISTICS

Over recommended operation free-air temperature range, $V_{CC} = 3.3 \pm 0.3$ V, $R_L = 200$ $\Omega$, $C_L = 4$ pF (unless otherwise noted) (see Figure 7 and Figure 9)

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>FROM (INPUT)</th>
<th>TO (OUTPUT)</th>
<th>MIN</th>
<th>TYP (1)</th>
<th>MAX</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>$t_{pd}$ (2)</td>
<td>A or B, C</td>
<td>B, C or A</td>
<td>40</td>
<td>ps</td>
<td></td>
<td></td>
</tr>
<tr>
<td>$t_{PZH}$, $t_{PLZ}$</td>
<td>SEL1</td>
<td>$A_{0.5}$ or $B_{0.5}$, $C_{0.5}$</td>
<td>2</td>
<td>ns</td>
<td>7</td>
<td></td>
</tr>
<tr>
<td></td>
<td>SEL2</td>
<td>$A_{6-11}$ or $B_{6-11}$, $C_{6-11}$</td>
<td>2</td>
<td>ns</td>
<td>7</td>
<td></td>
</tr>
<tr>
<td>$t_{PHZ}$, $t_{PLZ}$</td>
<td>SEL1</td>
<td>$A_{0.5}$ or $B_{0.5}$, $C_{0.5}$</td>
<td>2</td>
<td>ns</td>
<td>5</td>
<td></td>
</tr>
<tr>
<td></td>
<td>SEL2</td>
<td>$A_{6-11}$ or $B_{6-11}$, $C_{6-11}$</td>
<td>2</td>
<td>ns</td>
<td>5</td>
<td></td>
</tr>
<tr>
<td>$t_{sk(o)}$ (3)</td>
<td>A or B, C</td>
<td>B, C or A</td>
<td>6</td>
<td>30 ps</td>
<td></td>
<td></td>
</tr>
<tr>
<td>$t_{sk(p)}$ (4)</td>
<td>A or B, C</td>
<td>B, C or A</td>
<td>6</td>
<td>30 ps</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

(1) All typical values are at $V_{CC} = 3.3$V (unless otherwise noted), $T_A = 25^\circ$C.
(2) The propagation delay is the calculated RC time constant of the typical ON-State resistance of the switch and the specified load capacitance when driven by an ideal voltage source (zero output impedance).
(3) Output skew between center port ($A_{5}$, $A_{6}$) and any other channel.
(4) Skew between opposite transitions of the same output $|t_{PHL} - t_{PLH}|$

DYNAMIC CHARACTERISTICS

Over recommended operating free-air temperature range, $V_{CC} = 3.3 \pm 0.3$ V (unless otherwise noted)

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>TEST CONDITIONS</th>
<th>TYP (1)</th>
<th>UNIT</th>
</tr>
</thead>
<tbody>
<tr>
<td>$X_{TALK}$</td>
<td>$R_L = 50$ $\Omega$, $f = 250$ MHz (see Figure 11)</td>
<td>$-43$</td>
<td>dB</td>
</tr>
<tr>
<td>$O_{IRR}$</td>
<td>$R_L = 50$ $\Omega$, $f = 250$ MHz (see Figure 12)</td>
<td>$-42$</td>
<td>dB</td>
</tr>
<tr>
<td>BW</td>
<td>$R_L = 50$ $\Omega$, Switch ON (see Figure 10)</td>
<td>1.675</td>
<td>GHz</td>
</tr>
</tbody>
</table>

(1) All Typical Values are at $V_{CC} = 3.3$ V (unless otherwise noted), $T_A = 25^\circ$C.
OPERATING CHARACTERISTICS

Figure 3. Gain vs Frequency

Figure 4. Off Isolation vs Frequency

Figure 5. Crosstalk vs Frequency

Figure 6. $R_{ON}$ vs $V_{IN}$
PARAMETER MEASUREMENT INFORMATION

Enable and Disable Times

<table>
<thead>
<tr>
<th>TEST</th>
<th>VDD</th>
<th>S1</th>
<th>RL</th>
<th>Vin</th>
<th>CL</th>
<th>Vr</th>
</tr>
</thead>
<tbody>
<tr>
<td>tPLZ</td>
<td>3.3 V ± 0.3 V</td>
<td>2 × VDD</td>
<td>200 Ω</td>
<td>GND</td>
<td>4 pF</td>
<td>0.3 V</td>
</tr>
<tr>
<td>tPZH</td>
<td>3.3 V ± 0.3 V</td>
<td>GND</td>
<td>200 Ω</td>
<td>VDD</td>
<td>4 pF</td>
<td>0.3 V</td>
</tr>
</tbody>
</table>

NOTES:
A. CL includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Zo = 50 Ω, tR ≤ 2.5 ns, tF ≤ 2.5 ns.
D. The outputs are measured one at a time, with one transition per measurement.
E. tPLZ and tPZH are the same as tE.
F. tPZL and tPZH are the same as tE.

Figure 7. Test Circuit and Voltage Waveforms
Figure 8. Skew

VOLTAGE WAVEFORMS

<table>
<thead>
<tr>
<th>TEST</th>
<th>VCC</th>
<th>S1</th>
<th>RL</th>
<th>Vin</th>
<th>CL</th>
</tr>
</thead>
<tbody>
<tr>
<td>tsk(o)</td>
<td>3.3 V ± 0.3 V</td>
<td>Open</td>
<td>200 Ω</td>
<td>VCC or GND</td>
<td>4 pF</td>
</tr>
<tr>
<td>tsk(p)</td>
<td>3.3 V ± 0.3V</td>
<td>Open</td>
<td>200 Ω</td>
<td>VCC or GND</td>
<td>4 pF</td>
</tr>
</tbody>
</table>

NOTES:
A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control.
C. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
D. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_0 = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
E. The outputs are measured one at a time, with one transition per measurement.

Figure 9. Test Circuit and Voltage Waveforms
PARAMETER MEASUREMENT INFORMATION (continued)

Figure 10. Test Circuit for Frequency Response (BW)

Frequency response is measured at the output of the ON channel. For example, when \( V_{SEL} = 0 \) and \( A_0 \) is the input, the output is measured at \( B_0 \). All unused analog I/O ports are left open.

**HP8753ES Setup**

- Average = 4
- RBW = 3 kHz
- \( V_{BIAS} = 0.35 \) V
- ST = 2 s
- P1 = 0 dBm
PARAMETER MEASUREMENT INFORMATION (continued)

Figure 11. Test Circuit for Crosstalk (XTALK)

Crosstalk is measured at the output of the nonadjacent ON channel. For example, when VSEL = 0 and A1 is the input, the output is measured at A3. All unused analog input (A) ports are connected to GND, and output (B) ports are left open.

HP8753ES Setup

- Average = 4
- RBW = 3 kHz
- VBIAS = 0.35 V
- ST = 2 s
- P1 = 0 dBM
OFF isolation is measured at the output of the OFF channel. For example, when $V_{\text{SEL}} = \text{GND}$ and $A_1$ is the input, the output is measured at $1B_2$. All unused analog input (A) ports are connected to ground, and output (B) ports are left open.

**HP8753ES Setup**

- Average = 4
- RBW = 3 kHz
- $V_{\text{BIAS}} = 0.35$ V
- ST = 2 s
- P1 = 0 dBM
## REVISION HISTORY

Changes from Revision A (March 2012) to Revision B

<table>
<thead>
<tr>
<th>Change Description</th>
<th>Page</th>
</tr>
</thead>
<tbody>
<tr>
<td>Changed Low B Low Bit-to-Bit Skew in the FEATURES list from ( t_{ \text{sk}(p) } = 6 \text{ ps Max} ) to ( t_{ \text{sk}(p) } = 6 \text{ ps Typ} )</td>
<td>1</td>
</tr>
</tbody>
</table>
## PACKAGING INFORMATION

<table>
<thead>
<tr>
<th>Orderable Device</th>
<th>Status</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>Package Qty</th>
<th>Eco Plan (2)</th>
<th>Lead/Ball Finish (6)</th>
<th>MSL Peak Temp (3)</th>
<th>Op Temp (°C)</th>
<th>Device Marking (4/5)</th>
<th>Samples</th>
</tr>
</thead>
<tbody>
<tr>
<td>TS3DDR3812RUAR</td>
<td>ACTIVE</td>
<td>WQFN</td>
<td>RUA</td>
<td>42</td>
<td>3000</td>
<td>Green (RoHS &amp; no Sb/Br)</td>
<td>CU NIPDAU</td>
<td>Level-1-260C-UNLIM</td>
<td>-40 to 85</td>
<td>SL812</td>
<td></td>
</tr>
</tbody>
</table>

(1) The marketing status values are defined as follows:
- **ACTIVE**: Product device recommended for new designs.
- **LIFEBUY**: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
- **NRND**: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
- **PREVIEW**: Device has been announced but is not in production. Samples may or may not be available.
- **OBSOLETE**: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check [http://www.ti.com/productcontent](http://www.ti.com/productcontent) for the latest availability information and additional product content details.

- **TBD**: The Pb-Free/Green conversion plan has not been defined.

- **Pb-Free (RoHS)**: TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

- **Pb-Free (RoHS Exempt)**: This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

- **Green (RoHS & no Sb/Br)**: TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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## TAPE AND REEL INFORMATION

**Device**

- **TS3DDR3812RUAR**

**Package Type**

- WQFN

**Drawing**

- RUA

**Pins**

- 42

**SPQ**

- 3000

**Reel Diameter**

- 330.0

**Reel Width W1**

- 16.4

**A0**

- 3.8

**B0**

- 9.3

**K0**

- 1.0

**P1**

- 8.0

**W**

- 16.0

**Pin1 Quadrant**

- Q1

---

*All dimensions are nominal.*

---

**TAPE DIMENSIONS**

- A0: Dimension designed to accommodate the component width
- B0: Dimension designed to accommodate the component length
- K0: Dimension designed to accommodate the component thickness
- W: Overall width of the carrier tape
- P1: Pitch between successive cavity centers

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**

- **Sprocket Holes**
- **User Direction of Feed**
- **Pocket Quadrants**
### Tape and Reel Box Dimensions

*All dimensions are nominal*

<table>
<thead>
<tr>
<th>Device</th>
<th>Package Type</th>
<th>Package Drawing</th>
<th>Pins</th>
<th>SPQ</th>
<th>Length (mm)</th>
<th>Width (mm)</th>
<th>Height (mm)</th>
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<tbody>
<tr>
<td>TS3DDR3812RUAR</td>
<td>WQFN</td>
<td>RUA</td>
<td>42</td>
<td>3000</td>
<td>358.0</td>
<td>335.0</td>
<td>35.0</td>
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</tbody>
</table>

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www.ti.com 3-Aug-2017
NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. QFN (Quad Flatpack No-Lead) package configuration.
D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
THERMAL PAD MECHANICAL DATA

RUA (R–PWQFN–N42)  PLASTIC QUAD FLATPACK NO–LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No–Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

NOTE: All linear dimensions are in millimeters.
NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC-7351 is recommended for alternate designs.
D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.
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